

TOSHIBA SUPER FAST RECOVERY RECTIFIER SILICON DIFFUSED TYPE

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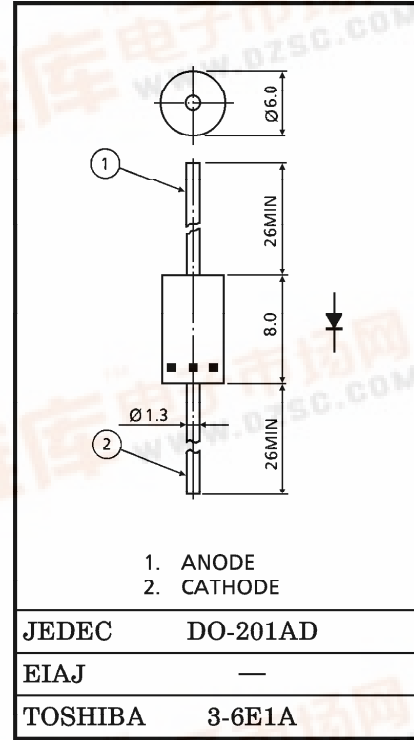
SWITCHING TYPE POWER SUPPLY APPLICATIONS

Unit in mm

- Repetitive Peak Reverse Voltage : $V_{RRM}=1000V$
- Average Forward Current : $I_F(AV)=2.0A$
- Very Fast Reverse-Recovery Time : $t_{rr}=100ns$

MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Repetitive Peak Reverse Voltage	V_{RRM}	1000	V
Average Forward Current	$I_F(AV)$	2.0	A
Peak One Cycle Surge Forward Current (Non-Repetitive)	I_{FSM}	70 (50Hz)	A
		77 (60Hz)	
Junction Temperature	T_j	-40~150	°C
Storage Temperature Range	T_{stg}	-40~150	°C



ELECTRICAL CHARACTERISTICS (Ta = 25°C)

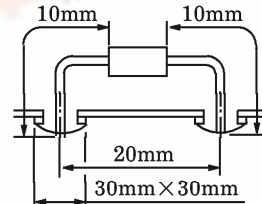
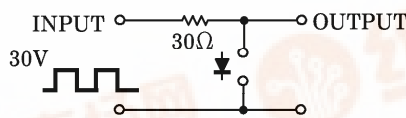
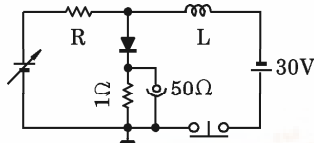
Weight : 1.18g

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Peak Forward Voltage	V_{FM}	$I_{FM}=3.0A$	—	—	3.0	V
Repetitive Peak Reverse Current	I_{RRM}	$V_{RRM}=1000V$	—	—	100	μA
Reverse Recovery Time (Note 1)	t_{rr}	$I_F=1A, di/dt = -30A/\mu s$	—	—	100	ns
Forward Recovery Time (Note 2)	t_{fr}	$I_F=1.0A$	—	300	—	ns
Thermal Resistance (Note 3)	$R_{th(j-a)}$	Junction to Ambient	—	—	37	°C/W
Thermal Resistance (Note 3)	$R_{th(j-l)}$	Junction to Lead	—	—	12	°C/W

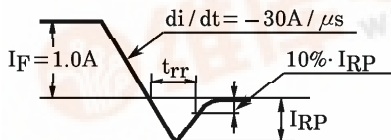
Note 1 : t_{rr} TEST CIRCUIT

Note 2 : t_{fr} TEST CIRCUIT

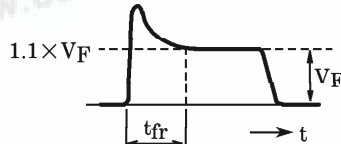
Note 3 : THERMAL RESISTANCE



WAVEFORM



WAVEFORM



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